
Contents

1	Electron Sources	1
1.1	Introduction and Definitions of Parameters	2
1.2	Schottky Sources	4
1.2.1	Emission Theory	4
1.2.2	Coulomb Interactions	6
1.2.3	Practical Aspects	7
1.3	Field Emission Sources	8
1.3.1	Emission Theory	8
1.3.2	Practical Aspects	10
1.4	Photo-Emission Sources	10
1.5	Effect of the Electron Source Parameters on Resolution in STEM	11
1.5.1	Contributions to the Probe Size	11
1.5.2	Current in a Probe	12
	Appendix	14
	References	15
2	In situ and Operando	17
2.1	General Principles	18
2.2	Some history	18
2.3	The Possibilities	19
2.3.1	Post-Mortem Characterization	20
2.3.2	Statistics	20
2.4	Time	22
2.4.1	Recording the Data	22
2.4.2	The CCD Camera	22
2.4.3	Direct-Detection Cameras	22
2.4.4	Software and Data Handling	23
2.4.5	Drift Correction	24
2.4.6	Ultrafast Electron Microscopy	25
2.5	The Environment	29

2.5.1	Ultrahigh Vacuum	36
2.5.2	Working in a Gas Cell	37
2.5.3	Working in a Liquid Cell	39
2.6	The Temperature	41
2.6.1	Temperature Measurement	41
2.6.2	Heating	42
2.6.3	Cooling	46
2.7	Other Stimuli	48
2.7.1	Deformation	48
2.7.2	Magnetic Fields	55
2.7.3	Electric Fields	56
2.7.4	Photons	64
2.8	Adding or Removing Material	67
2.8.1	Depositing Layers/Particles	67
2.8.2	Deposition Energy: Electron and Ion Irradiation	68
2.9	The Future	73
Appendix	Appendix	75
References	References	76
3	Electron Diffraction and Phase Identification	81
3.1	Introduction	82
3.2	Spinodal Alloys	83
3.2.1	Example: Ordered FeBe Phases and A2 Matrix	83
3.3	Superalloys with Ordered Precipitates	85
3.3.1	Example: γ'' and γ' Precipitation in Alloy 718	87
3.3.2	Example: D0 ₃ -Ordered δ Precipitation in Alloy 718	89
3.4	Carbide Precipitation in fcc Alloys	93
3.4.1	Example: M ₂₃ C ₆ Precipitation in a Ni-Based Alloy	93
3.4.2	Example: MC Carbides in a Ni-Based Alloy	94
3.5	Ferritic Steels	96
3.5.1	Relationships Between Austenite and Ferrite, Austenite and Martensite (fcc/bcc)	96
3.5.2	Relationship Between Cementite (Orthorhombic Fe ₃ C or M ₃ C) and Ferrite/Tempered Martensite	97
3.5.3	Relationships Between Alloy Carbides and Ferrite	97
3.5.4	Precipitation in Ferritic Structures	98
3.6	Epitaxial Oxide on Metal: Presence of Fe ₃ O ₄ on Steel Foils	99
Appendix	Appendix	101
References	References	102

4	Convergent-Beam Electron Diffraction: Symmetry and Large-Angle Patterns	103
4.1	Symmetry	104
4.2	Point-Group Determination	104
4.3	Space-Group Determination	109
4.3.1	Forbidden Reflections	109
4.3.2	Black Crosses	111
4.3.3	Complete Procedure for Space-Group Determination	113
4.4	Ni ₃ Mo – A Worked Example	114
4.4.1	Ni ₃ Mo – a Worked Example, Part I: Point Group	114
4.4.2	Qualifications	118
4.4.3	Ni ₃ Mo – a Worked Example, Part II: Space Group	119
4.5	Additional and Alternative Symmetry Methods	120
4.5.1	Symmetry Determination from Off-Axis Patterns	120
4.5.2	Symmetry from Precession Patterns	122
4.6	More on Glide Planes	123
4.6.1	GM Lines in HOLZ Reflections	124
4.6.2	Glide Planes Normal to the Beam	124
4.7	Beyond Symmetry	124
4.7.1	Enantiomorphous Pairs: Handedness	126
4.7.2	Polarity	126
4.7.3	Coherent Convergent-Beam Diffraction	127
4.8	Tanaka Methods	127
4.9	LACBED	127
4.9.1	The Nature of LACBED Patterns	129
4.9.2	Obtaining LACBED Patterns in Practice	130
4.9.3	Choosing the Parameters	131
4.10	Spherical Aberration and LACBED	132
4.11	Crystal Defects in LACBED Patterns: Dislocations	132
4.12	Crystal Defects in LACBED Patterns: Stacking Faults and Antiphase Boundaries	134
4.13	Other Tanaka Methods	134
4.13.1	Bright- and Dark-Field LACBED	134
4.13.2	Convergent-Beam Imaging (CBIM)	136
4.13.3	Rastering Techniques	137
Appendix	Appendix	141
References	References	142

5	Electron Crystallography, Charge-Density Mapping, and Nanodiffraction	145
5.1	Can We Quantify Electron Diffraction Data?	146
5.2	Quantitative CBED for Charge-Density Mapping	147
5.3	Strain Mapping, High Voltage, Lattice Parameters Measured by QCBED	153
5.4	Spot Patterns – Solving Crystal Structures	155
5.5	The Precession Method	157
5.6	Diffuse Scattering, Defects, Phonons, and Phase Transitions	158
5.7	Diffractive Imaging, Ptychography, STEM Holography, Ronchigrams, and All That	159
5.8	Equipment for Quantitative Electron Diffraction	162
Appendix	163
References	164
6	DigitalMicrograph	167
6.1	Introduction	168
6.1.1	What Is DigitalMicrograph?	168
6.1.2	Installing DigitalMicrograph Offline	168
6.1.3	A (Very) Quick Overview	168
6.2	Understanding Data	170
6.2.1	What is an Image?	170
6.2.2	Image Display	171
6.2.3	Number Formats	173
6.2.4	Image Calibration and Image Tags	178
6.2.5	Some Simple Tools	180
6.2.6	Extracting Subsets of Data	181
6.3	Digital Image Processing	183
6.3.1	Image ‘Filters’	185
6.3.2	Fourier Transformation in Images	187
6.3.3	Fourier Filtering	189
6.3.4	Coordinate Transformations	192
6.4	Scripting and Plugins	193
Appendix	195
References	195
7	Electron Waves, Interference, and Coherence	197
7.1	Introduction	198
7.2	Description of Waves	198
7.2.1	Plane Wave	199

7.2.2	Spherical Wave	199
7.2.3	Modulated Wave	199
7.3	Interference	200
7.4	Modulation of a Wave by an Object	201
7.5	Propagation of Waves	201
7.5.1	Fresnel Approximation in the Near-Field of the Object	202
7.5.2	Fraunhofer Approximation in the Far-Field of the Object	202
7.6	Imaging: Formation of the Image Wave	203
7.6.1	Fourier Transform of the Object Exit Wave	203
7.6.2	Building the Image Wave by Inverse Fourier Transform of the Fourier Spectrum	203
7.7	Electron Wave Function	204
7.8	Electron Interference	205
7.9	Findings	206
7.10	Interpretation	207
7.11	Coherence	207
7.11.1	Spatial Coherence	208
7.11.2	Coherent Current	210
7.11.3	Temporal Coherence	211
7.11.4	Total Degree of Coherence	211
7.11.5	A Generalization	211
7.11.6	Coherence at Inelastic Interaction	211
Appendix	213
References	213
8	Electron Holography	215
8.1	Big Problem with TEM: Phase Contrast	216
8.2	Wave Modulation and Conventional Imaging	216
8.2.1	Amplitude Modulation	216
8.2.2	Phase Modulation	217
8.2.3	What Do We See in an Electron Image?	218
8.3	Principle of Image-Plane Off-Axis Holography	219
8.3.1	Recording a Hologram	219
8.3.2	Reconstructing the Object Exit-Wave	220
8.3.3	What Have We Achieved so Far?	223
8.4	Properties of the Reconstructed Object Exit-Wave	223
8.5	Requirements of Holography	224
8.6	Quality Criteria	224

8.7	Application to Electric Potentials on Nanometer Scale	225
8.7.1	Phase Shift Due to Electrostatic Potentials	225
8.7.2	Experimental Considerations	226
8.7.3	Application Example: p-n Junctions	227
8.8	Further Derivatives of Electron Holography	227
8.8.1	Holographic Tomography	227
8.8.2	Dark-Field Holography	228
Appendix	230
References	230
9	Focal-Series Reconstruction	233
9.1	Motivation: Why the Effort?	234
9.2	Quick Walk Through Electron Diffraction	235
9.3	From the Wavefunction to the Image	237
9.3.1	Imaging with a 'Neutral' Microscope	238
9.3.2	Linear Imaging with a Constant-Phase-Shift Microscope .	240
9.3.3	Linear Imaging with a Real Microscope	241
9.3.4	From Oscillations to Windings: an Integral View on Linear Imaging	247
9.4	From the Images to the Wavefunction	249
9.4.1	Tomographic Interpretation of Focal Series	249
9.4.2	Fundamental Properties of Focal Series	250
9.4.3	An Explicit Solution to the Linear Inversion Problem . .	253
9.4.4	Nonlinear Reconstruction	255
9.4.5	Numerical Correction of Residual Aberrations	256
9.5	Application Examples	257
9.5.1	Twin Boundaries in BaTiO ₃	258
9.5.2	Stacking Fault in GaAs	260
Appendix	263
References	264
10	Direct Methods for Image Interpretation	267
10.1	Introduction	268
10.2	Basics of Image Formation	268
10.2.1	Real imaging	268
10.2.2	Successive Imaging Steps	269
10.2.3	Coherent Imaging	269
10.2.4	High-Resolution Imaging in the TEM	270
10.3	Focal-Series Reconstruction of the Exit Wave	271

10.4	Interpretation of the Reconstructed Exit Wave	271
10.4.1	Electron Channeling	272
10.4.2	Argand Plot	273
10.5	Quantitative Structure Refinement	274
10.5.1	Precision Versus Resolution	276
10.5.2	Quantitative Model-Based Structure Determination . .	276
Appendix	280
References	280
11	Imaging in STEM	283
11.1	Z-Contrast STEM: an Introduction	284
11.1.1	Independent Scatterers	284
11.1.2	An Array of Scatterers	284
11.1.3	As the Crystal Thickens	284
11.1.4	Inside and Outside	286
11.1.5	The Effect of Defects	287
11.1.6	Quasicrystals	288
11.2	An Electron's Eye View of STEM	288
11.2.1	Plane Waves and Probes	291
11.2.2	Rayleigh, Airy and Resolution	292
11.3	Lens Aberrations for STEM	293
11.3.1	The Benefits of Aberration Correction	295
11.3.2	Resolution in the Third Dimension – Depth Resolution .	300
11.4	Spatial and Temporal Incoherence	305
11.4.1	Spatial Incoherence	305
11.4.2	Temporal Incoherence	306
11.4.3	"How Do I Know if I Have a Coherent Probe?" The Ronchigram	306
11.5	Coherent or Incoherent Imaging	310
11.5.1	A Point Detector; Coherent Imaging	311
11.5.2	An Infinite Detector: Incoherent Imaging	312
11.5.3	An Annular Detector: Incoherent Dark-Field or Bright-Field Imaging	314
11.5.4	Atoms Are Smaller in HAADF STEM	315
11.5.5	Transverse Coherence	316
11.5.6	The Origin of Contrast in the Scanned Image	317
11.5.7	Transfer Function and Damping Function	318
11.5.8	Longitudinal Coherence	319

11.6	Dynamical Diffraction	323
11.7	Other Sources of Image Contrast	326
11.8	Image Processing	329
11.9	Image Simulation	332
11.9.1	Bloch Waves	333
11.9.2	Multislice	333
11.9.3	Bloch Waves with Absorption	333
11.9.4	There Is No Stobbs Factor in HAADF	334
11.10	Future Directions	335
	Appendix	337
	References	338
12	Electron Tomography	343
12.1	Theory of Projection	344
12.2	Back-Projection	346
12.3	Constrained Reconstruction	347
12.3.1	Constraint by Projection Consistency	347
12.3.2	Constraint by Discrete Methods	348
12.3.3	Constraint by Symmetry	348
12.3.4	Metric-Based Constraint	348
12.4	Other Reconstruction Approaches	350
12.5	Meeting the Projection Requirement	350
12.6	STEM Tomography	351
12.7	Element-Selected Tomography	354
12.8	Dark-Field TEM Tomography	356
12.9	Holographic Tomography	358
12.10	Atomistic Tomography	359
12.11	Experimental Limitations	360
12.12	Beam Damage and Contamination	364
12.13	Automated Acquisition	365
12.14	Tilt-Series Alignment	366
12.15	Visualization of Three-Dimensional Datasets	368
12.16	Segmentation	369
12.17	Quantitative Analysis of Volumetric Data	371
	Appendix	373
	References	373
13	EFTEM	377
13.1	Introduction	378
13.2	Why Use EFTEM?	378

13.3	Instrumentation for EFTEM	379
13.3.1	General TEM Considerations	379
13.3.2	The Imaging Filter	379
13.3.3	Detector Considerations	380
13.4	Limitations and Artefacts	381
13.4.1	Spatial Resolution in EFTEM Images	381
13.4.2	Non-Isochromaticity	383
13.4.3	Sample Drift	383
13.4.4	Diffraction Contrast	384
13.4.5	Illumination Convergence	384
13.5	Application of EFTEM	385
13.5.1	Zero-Loss Imaging and Diffraction	385
13.5.2	Measuring Relative Thickness (t/λ Mapping)	386
13.6	Core-Loss Elemental Mapping	387
13.6.1	Elemental Mapping (Three-Window Method)	387
13.6.2	Jump-Ratio Mapping (Two-Window Method)	388
13.7	EFTEM Spectrum-Imaging	389
13.8	Low-Loss Imaging	392
13.9	Alternative Imaging Techniques for Biological Specimens	393
13.10	Quantitative Elemental Mapping	394
13.11	Chemical State Mapping Using ELNES	396
13.12	Hybrid EFTEM Modes (ω - q , Line Spectrum EFTEM)	397
13.13	EFTEM Tomography	398
	Appendix	401
	References	401
14	Calculating EELS	405
14.1	Introduction	406
14.2	Density Functional Theory (DFT)	407
14.2.1	Introduction to DFT	407
14.2.2	The Exchange Correlation Potential	409
14.2.3	Approximations to the Potential	409
14.2.4	Basis Sets	410
14.2.5	The Korringa–Kohn–Rostoker (KKR) Method	412
14.3	Calculations of the ELNES	412
14.3.1	ELNES Theory	412
14.3.2	The Core Hole	414
14.3.3	Multiplet Theory	415
14.3.4	Multiple Scattering (MS) Methods	416

14.4 Calculating Low-Loss EELS	417
Appendix	421
References	422
15 Diffraction & X-ray Excitation	425
15.1 Introduction	426
15.2 ALCHEMI	426
15.3 Gedanken ALCHEMI	426
15.4 Two Examples	428
15.4.1 Dilute Solution/Partition Coefficient Analysis	428
15.4.2 Concentrated Solution/OTL Analysis	430
15.5 Delocalization and Axial Channeling	431
15.6 Optimizing ALCHEMI: ‘Statistical’ ALCHEMI	432
15.7 Incoherent Channeling Patterns	432
15.8 Vacancies and Interstitials	432
15.9 Chemistry	434
Appendix	435
References	436
16 X-ray and EELS Imaging	439
16.1 What Are Spectral Images and Why Should We Collect Them?	440
16.2 Some History	441
16.3 Acquisition and Analysis of Spectral Images	442
16.3.1 Sampling and the Effect of Probe Versus Pixel Size (STEM-XEDS/EELS) or Magnification (EFTEM)	442
16.3.2 Signal: Count Rate, Dwell Time, Spectral Image Size, and Acquisition Time	443
16.3.3 Drift Correction and Beam Damage	446
16.3.4 Conventional Data Analysis Methods	446
16.4 Multivariate Statistical Analysis Methods	451
16.4.1 Principal Components Analysis (PCA)	454
16.4.2 Factor Rotations	455
16.4.3 Multivariate Curve Resolution (MCR)	456
16.4.4 Quantification	457
16.5 Example of X-ray and Electron Energy-Loss Spectral Image Acquisition and Analysis	458
16.5.1 Fe-Ni Spectral Image Acquisition and Quantification	458
16.5.2 Mn-Doped SrTiO ₃ Grain Boundary Spectral Image Acquisition and Quantification	459
16.5.3 Plasmon Mapping of AG Nanorods: EELS Spectral Image Analysis	462

Appendix	464
References	464
17 Practical Aspects and Advanced Applications of XEDS	467
17.1 Performance Parameters of XEDS Detectors	468
17.1.1 Detector, Fundamental Parameters	468
17.1.2 Monitoring Detector Contamination	470
17.1.3 Software to Determine Detector Parameters	471
17.2 X-ray Spectrum Simulation – a Tutorial and Applications of DTSA	472
17.2.1 What Is DTSA?	473
17.2.2 A Brief Tutorial of X-ray Spectrum Simulation for a Thin Specimen Using DTSA	475
17.2.3 Details of X-ray Simulation in DTSA	477
17.2.4 Application 1: Confirmation of Peak Overlap	481
17.2.5 Application 2: Evaluation of X-ray Absorption into a Thin Specimen	482
17.2.6 Application 3: Evaluation of the AEM-XEDS Interface	483
17.2.7 Application 4: Estimation of the Detectability Limits	483
17.3 The ζ -factor Method: a New Approach for Quantitative X-ray Analysis of Thin Specimens	486
17.3.1 Why Bother with Quantification?	486
17.3.2 What Is the ζ -factor?	487
17.3.3 Quantification Procedure in the ζ -factor Method	488
17.3.4 Determination of ζ factors	489
17.3.5 Applications of ζ -factor Method	490
17.4 Contemporary Applications of X-ray Analysis	492
17.4.1 Renaissance of X-ray Analysis	493
17.4.2 XEDS Tomography for 3D Elemental Distribution	494
17.4.3 Atomic Resolution X-ray Mapping	495
Appendix	500
References	501
Figure and Table Credits	505
Index	515